


<b>Search Notes</b> 	<b>Application/Control No.</b> 10585638	<b>Applicant(s)/Patent Under Reexamination</b> OHNO ET AL.
	<b>Examiner</b> JONATHAN HAN	<b>Art Unit</b> 4176

SEARCHED			
Class	Subclass	Date	Examiner
257	421	12/01/2008	Jonathan Han
257	295	12/1/2008	Jonathan Han
257	E43.001	12/1/2008	Jonathan Han
257	E43.005	12/1/2008	Jonathan Han
257	E29.167	12/1/2008	Jonathan Han
257	E29.323	12/1/2008	JJH
257	295,E43.001-E43.007,E27.005-E27.006,E27.008,E29.164,E29.167,E29.272,E29.323	07/13/2009	JJH
257	81,82,116,117,432-437,457,459,749,421-422	07/13/2009	JJH

SEARCH NOTES		
Search Notes	Date	Examiner
Reviewed IDS and ISR form	12/01/2008	Jonathan Han
Performed Inventor and Assignee Search via eDAN	12/01/2008	Jonathan Han
Performed Class/Subclass Search (see attached EAST Search History)	12/01/2008	Jonathan Han
Performed Text Search	12/01/2008	Jonathan Han
Performed Second Class Search	07/13/2009	JJH
Performed Text Search (see attached EAST Search History)	07/13/2009	JJH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/JONATHAN HAN/  
Examiner,Art Unit 2818